

IGBT

SGH20N120RUFD

Short Circuit Rated IGBT

General Description

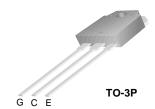
Fairchild's RUFD series of Insulated Gate Bipolar Transistors (IGBTs) provides low conduction and switching losses as well as short circuit ruggedness. The RUFD series is designed for applications such as motor control, uninterrupted power supplies (UPS) and general inverters where short circuit ruggedness is a required feature.

Features

- Short circuit rated 10 μ s @ T_C = 100°C, V_{GE} = 15V
- High speed switching
- Low saturation voltage : $V_{CE(sat)} = 2.3 \text{ V} @ I_C = 20A$
- High input impedance
- CO-PAK, IGBT with FRD : t_{rr} = 80ns (typ.)

Applications

AC & DC motor controls, general purpose inverters, robotics, and servo controls.





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Description		SGH20N120RUFD	Units
V _{CES}	Collector-Emitter Voltage		1200	V
V _{GES}	Gate-Emitter Voltage		± 25	V
	Collector Current	@ $T_C = 25^{\circ}C$	32	Α
IC	Collector Current	@ T _C = 100°C	20	А
I _{CM (1)}	Pulsed Collector Current	-	60	Α
I _F	Diode Continuous Forward Current	@ T _C = 100°C	20	Α
I _{FM}	Diode Maximum Forward Current		120	Α
T _{SC}	Short Circuit Withstand Time	@ T _C = 100°C	10	μs
P_{D}	Maximum Power Dissipation	@ $T_C = 25^{\circ}C$	230	W
	Maximum Power Dissipation	@ T _C = 100°C	92	W
TJ	Operating Junction Temperature		-55 to +150	°C
T _{stg}	Storage Temperature Range		-55 to +150	°C
T _L	Maximum Lead Temp. for soldering Purposes, 1/8" from case for 5 seconds		300	°C

Notes :

(1) Repetitive rating : Pulse width limited by max. junction temperature

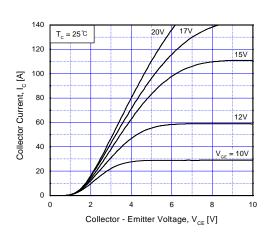
Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Units
R _{θJC} (IGBT)	Thermal Resistance, Junction-to-Case		0.54	°C/W
$R_{\theta JC}(DIODE)$	Thermal Resistance, Junction-to-Case 0.84		°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		40	°C/W

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Chai	racteristics					
BV _{CES}	Collector-Emitter Breakdown Voltage	$V_{GE} = 0V$, $I_C = 1mA$	1200			V
$\Delta B_{VCES}/$ ΔT_J	Temperature Coefficient of Breakdown Voltage	$V_{GE} = 0V$, $I_C = 1mA$		0.6		V/°C
I _{CES}	Collector Cut-Off Current	$V_{CE} = V_{CES}$, $V_{GE} = 0V$			1	mA
I _{GES}	G-E Leakage Current	$V_{GE} = V_{GES}, V_{CE} = 0V$			± 100	nA
On Char	acteristics					
V _{GE(th)}	G-E Threshold Voltage	$I_C = 20$ mA, $V_{CE} = V_{GE}$	3.5	5.5	7.5	V
*GE(th)	Collector to Emitter	$I_C = 20A$, $V_{GE} = 15V$		2.3	3.0	V
$V_{CE(sat)}$	Saturation Voltage	$I_C = 32A$, $V_{GE} = 15V$		2.8		V
		, <u>GE</u>				
	C Characteristics	1		0000		_
C _{ies}	Input Capacitance	$V_{CE} = 30V_{V_{GE}} = 0V_{V_{GE}}$		2000		pF
C _{oes}	Output Capacitance Reverse Transfer Capacitance	f = 1MHz		170 60		pF pF
	ng Characteristics	T				
t _{d(on)}	Turn-On Delay Time			30		ns
t _r	Rise Time	1		60		ns
t _{d(off)}	Turn-Off Delay Time	$V_{CC} = 600 \text{ V}, I_{C} = 20\text{A},$		70	130	ns
t _f	Fall Time	$R_G = 15\Omega, V_{GE} = 15V,$		150	300	ns
E _{on}	Turn-On Switching Loss	Inductive Load, T _C = 25°C		1.30		mJ
E _{off}	Turn-Off Switching Loss	1		1.30		mJ
E _{ts}	Total Switching Loss	1		2.60	3.65	mJ
t _{d(on)}	Turn-On Delay Time			30		ns
t _r	Rise Time	1		70		ns
t _{d(off)}	Turn-Off Delay Time	$V_{CC} = 600 \text{ V}, I_{C} = 20\text{A},$		90	165	ns
t _f	Fall Time	$R_G = 15\Omega, V_{GE} = 15V,$		200	400	ns
E _{on}	Turn-On Switching Loss	Inductive Load, T _C = 125°C		1.50		mJ
E _{off}	Turn-Off Switching Loss	1		2.00		mJ
E _{ts}	Total Switching Loss	1		3.50	5.08	mJ
T _{sc}	Short Circuit Withstand Time	V _{CC} = 600 V, V _{GE} = 15V @ T _C = 100°C	10			μs
Q _q	Total Gate Charge			95	140	nC
Q _{ge}	Gate-Emitter Charge	$V_{CE} = 600 \text{ V}, I_{C} = 20\text{A},$		15	25	nC
Q _{qc}	Gate-Collector Charge	V _{GE} = 15V		43	65	nC
90	Ü	Measured 5mm from PKG		14		nН

Electrical Characteristics of DIODE $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Units
V	Diode Forward Voltage	I _F = 20A	$T_C = 25^{\circ}C$		2.8	3.5	V
V_{FM}			T _C = 100°C		2.5		
+	Diode Reverse Recovery Time		$T_C = 25^{\circ}C$		80	110	nc
^t rr	Diode Reverse Recovery Time	dI/dt=200 A/μs	T _C = 100°C		95		ns
	Diode Peak Reverse Recovery		$T_C = 25^{\circ}C$		8.0	10.0	Α
¹ rr	Current		T _C = 100°C		9.5		A
0	Diode Reverse Recovery Charge		$T_C = 25^{\circ}C$		320	500	nC
Q_{rr}			T _C = 100°C	-	450		110



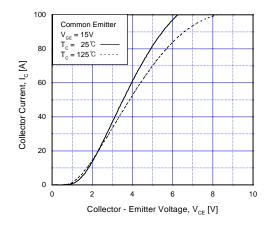
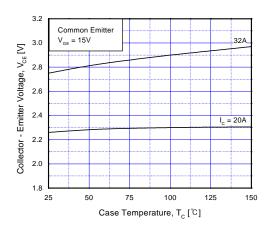


Fig 1. Typical Output Characteristics

Fig 2. Typical Saturation Voltage Characteristics



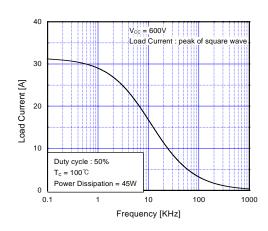
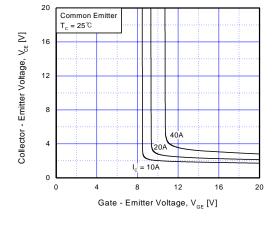


Fig 3. Saturation Voltage vs. Case
Temperature at Variant Current Level

Fig 4. Load Current vs. Frequency



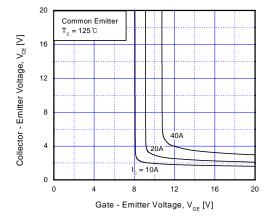


Fig 5. Saturation Voltage vs. V_{GE}

Fig 6. Saturation Voltage vs. $V_{\rm GE}$

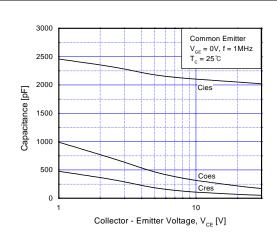
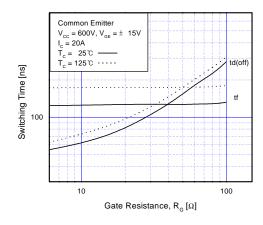


Fig 7. Capacitance Characteristics

Fig 8. Turn-On Characteristics vs.
Gate Resistance



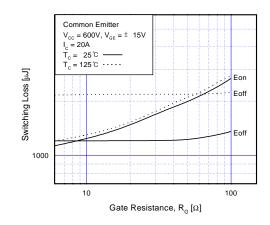
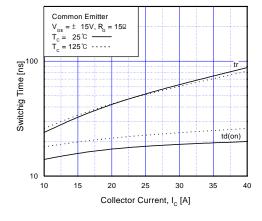


Fig 9. Turn-Off Characteristics vs.
Gate Resistance

Fig 10. Switching Loss vs. Gate Resistance



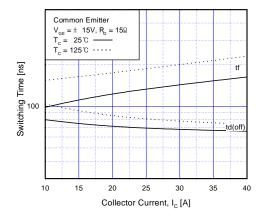
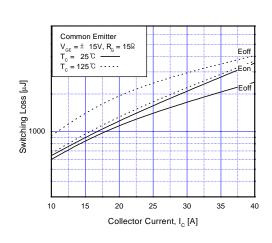


Fig 11. Turn-On Characteristics vs. Collector Current

Fig 12. Turn-Off Characteristics vs. Collector Current



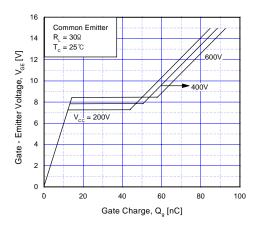
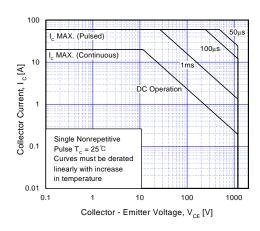


Fig 13. Switching Loss vs. Collector Current

Fig 14. Gate Charge Characteristics



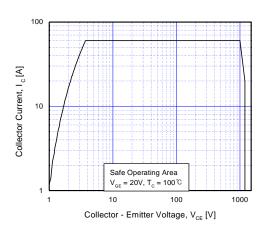


Fig 15. SOA Characteristics

Fig 16. Turn-Off SOA

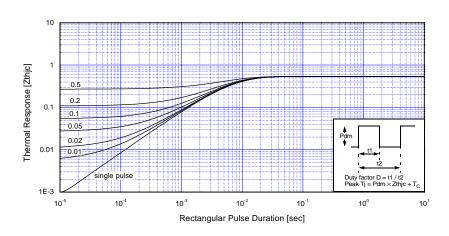
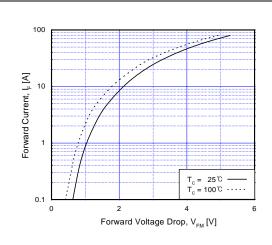


Fig 17. Transient Thermal Impedance of IGBT



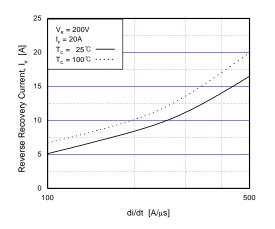
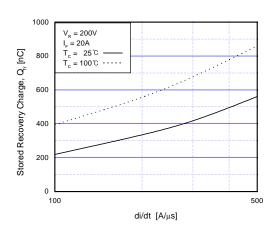


Fig 18. Forward Characteristics

Fig 19. Reverse Recovery Current



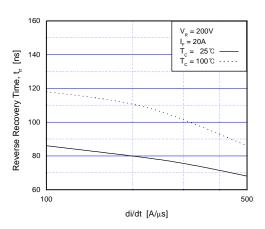
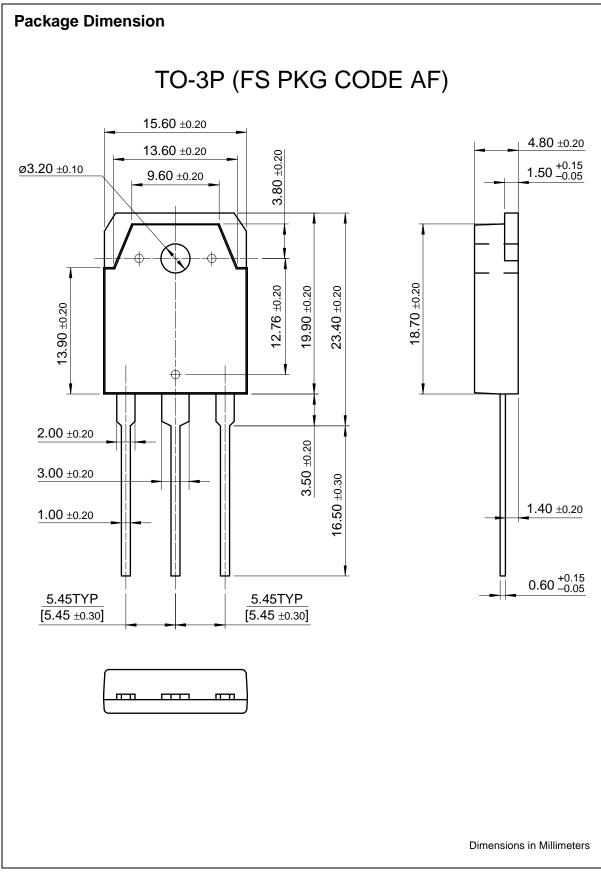


Fig 20. Stored Charge

Fig 21. Reverse Recovery Time



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